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**Development of cap-free sputtered GeTe films for inline phase change switch based RF circuits**

Matthew R. King, Brian P. Wagner, Evan B. Jones, Nabil El-Hinnawy, Pavel Borodulin, Sean R. McLaughlin, John S. Mason Jr., Robert S. Howell, Michael J. Lee and Robert M. Young  
J. Vac. Sci. Technol. B **32**, 041204 (2014); <http://dx.doi.org/10.1116/1.4883217>

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**Dual-superlattice calibrations for group-III species in III-V semiconductor epitaxial structure growth**

Richard P. Leavitt, Lei He and Christopher J. K. Richardson  
J. Vac. Sci. Technol. B **32**, 041205 (2014); <http://dx.doi.org/10.1116/1.4887482>

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**Isotope effects on plasma species of Ar/H<sub>2</sub>/D<sub>2</sub> plasmas**

Nick Fox-Lyon and Gottlieb S. Oehrlein  
J. Vac. Sci. Technol. B **32**, 041206 (2014); <http://dx.doi.org/10.1116/1.4889858>

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**Fabrication of sub-200 nm AlN-GaN-AlN waveguide with cleaved end facet**

Yijing Chen, Vivek Krishnamurthy, Yicheng Lai, Yi Luo, Zhibiao Hao, Lai Wang and Seng-Tiong Ho  
J. Vac. Sci. Technol. B **32**, 041207 (2014); <http://dx.doi.org/10.1116/1.4890487>

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**LITHOGRAPHY****Electron scattering analysis based on electron ray-tracing in extreme ultraviolet photomask**

Jin Choi, Byung Sup Ahn and Chan Uk Jeon  
J. Vac. Sci. Technol. B **32**, 041601 (2014); <http://dx.doi.org/10.1116/1.4878943>

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**Focused ion beam direct patterning of hardmask layers**

Simon Waid, Heinz D. Wanzenboeck, Michael Muehlberger, Marco Gavagnin and Emmerich Bertagnolli  
J. Vac. Sci. Technol. B **32**, 041602 (2014); <http://dx.doi.org/10.1116/1.4884777>

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**NANOMETER SCIENCE & TECHNOLOGY****Ni<sub>2.36</sub>Mn<sub>0.72</sub>Ga<sub>0.92</sub> nanowires with high martensite transition temperature**

Parshu Gyawali, Keshab Sapkota, Ian Pegg and John Philip







